

OptiMOS®-P2 Power-Transistor

AEC[®] • Qualified



Features

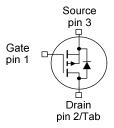
- P-channel Logic Level Enhancement mode
- AEC qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green package (RoHS compliant)
- 100% Avalanche tested
- Intended for reverse battery protection

Product Summary

V_{DS}	-30	٧
R _{DS(on)}	6.8	mΩ
I_{D}	-80	А







Туре	Package	Marking		
IPD80P03P4L-07	PG-TO252-3-11	4P03L07		

Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25°C, V _{GS} =-10V ¹⁾	-80	А
		T _C =100°C, V _{GS} =-10V ²⁾	-65	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25°C	-320	1
Avalanche energy, single pulse	E _{AS}	I _D =-40A	135	mJ
Avalanche current, single pulse	IAS	-	-80	А
Gate source voltage	V_{GS}	-	+5/-16	V
Power dissipation	P_{tot}	T _C =25 °C	88	W
Operating and storage temperature	$T_{\rm j}$, $T_{\rm stg}$	-	-55 +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	



Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	1.7	K/W
SMD version, device on PCB	R_{thJA}	minimal footprint	-	-	62	
		6 cm ² cooling area ³⁾	-	-	40	

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V_{GS} =0V, I_D = -1mA	-30	1	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -130 \mu {\rm A}$	-1.0	-1.5	-2.0	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =-24V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C	-	-0.03	-1	μA
		V_{DS} =-24V, V_{GS} =0V, T_{j} =125°C ²⁾	-	-10	-100	
Gate-source leakage current	I _{GSS}	V _{GS} =-16V, V _{DS} =0V	-	-	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =-4.5V, I _D =-40A	-	8.7	12	mΩ
		V _{GS} =-10V, I _D =-80A	-	5.6	6.8	



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	4400	5700	pF
Output capacitance	Coss	$V_{\rm GS}$ =0V, $V_{\rm DS}$ =-25V, f =1MHz	-	1220	1600	1
Reverse transfer capacitance	C _{rss}]	-	30	60	
Turn-on delay time	t _{d(on)}		-	8	-	ns
Rise time	t _r	V _{DD} =-15V,	-	4	-	
Turn-off delay time	$t_{\text{d(off)}}$	$V_{\rm GS}$ =-10V, $I_{\rm D}$ =-80A, $R_{\rm G}$ =3.5 Ω	-	15	-	
Fall time	t_{f}]	-	60	-	
Gate Charge Characteristics ²⁾			1	T	Ī	
Gate to source charge	Q _{gs}		-	16	20	nC
Gate to drain charge	Q_{gd}	V _{DD} =-24V, I _D =-80A,	-	8	16	
Gate charge total	Qg	V _{GS} =0 to -10V	-	63	80	
Gate plateau voltage	V _{plateau}		-	-3.7	-	V
Reverse Diode						
Diode continous forward current ²⁾	Is	- T _C =25°C	-	-	-80	А
Diode pulse current ²⁾	I _{S,pulse}	7 C=20 C	-	-	-320	1
Diode forward voltage	V_{SD}	V _{GS} =0V, I _F =-80A, T _j =25°C	-	-	-1.3	V
Reverse recovery time ²⁾	t _{rr}	V _R =-15V, I _F =-40A,	-	50	-	ns
Reverse recovery charge ²⁾	Qrr	$di_F/dt = -100A/\mu s$	-	40	-	nC

 $^{^{1)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ = 1.7K/W the chip is able to carry 92A at 25°C.

²⁾ Defined by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.

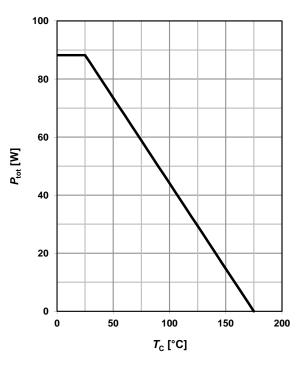


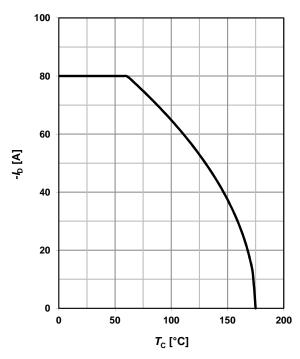
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \le -6V$$

2 Drain current

$$I_D = f(T_C); V_{GS} \le -6V$$





3 Safe operating area

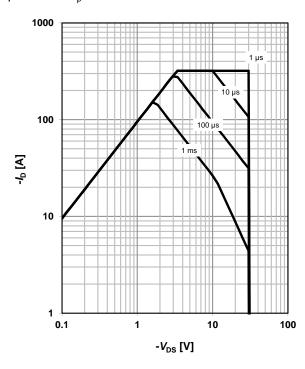
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

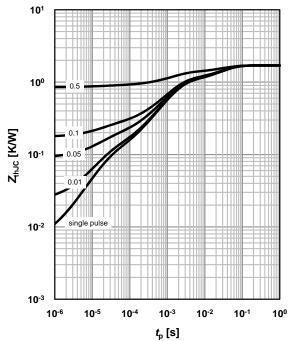
parameter: $t_{\rm p}$

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter: $D=t_p/T$







5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 \text{ }^{\circ}\text{C}$

parameter: $V_{\rm GS}$

240 240 4.5V 40 40 40 40 40 30 30 30 30

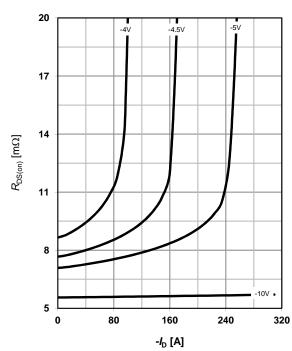
2

 $-V_{\rm DS}$ [V]

6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}$

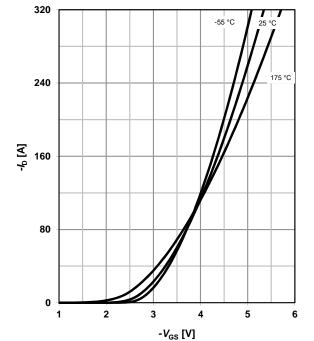
parameter: V_{GS}



7 Typ. transfer characteristics

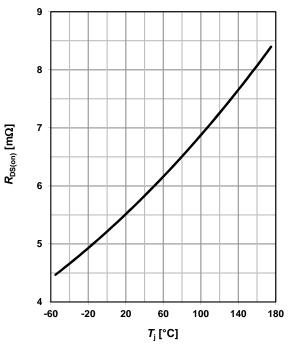
 $I_{D} = f(V_{GS}); V_{DS} = -6V$

parameter: $T_{\rm j}$



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = -80 \text{ A}; V_{GS} = -10 \text{ V}$$





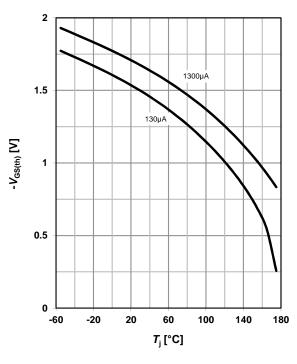
9 Typ. gate threshold voltage

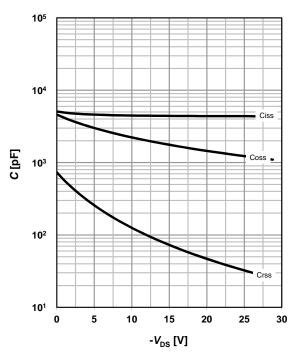
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: -I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$





11 Typical forward diode characteristicis

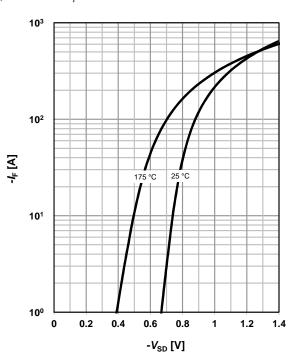
 $IF = f(V_{SD})$

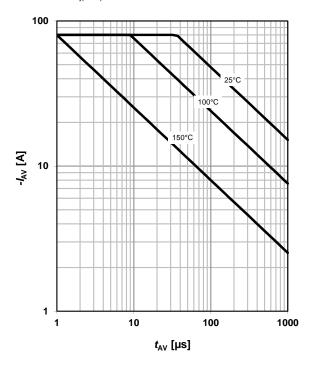
parameter: $T_{\rm j}$

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: $T_{j(start)}$







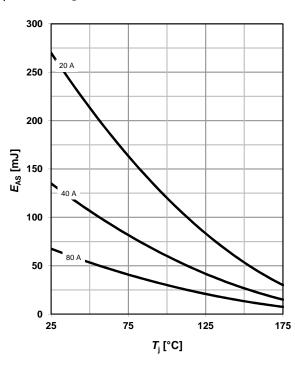
13 Avalanche energy

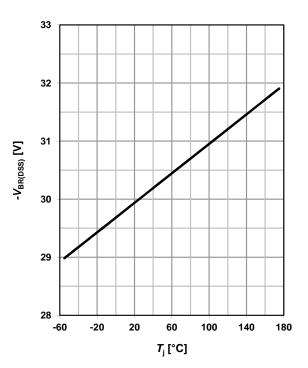
$E_{AS} = f(T_j)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = -1 \text{ mA}$$



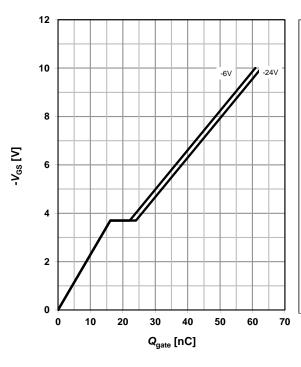


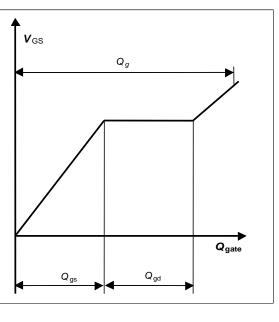
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = -80 \text{ A pulsed}$

parameter: V_{DD}

16 Gate charge waveforms







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Revision History

Version		Date	Changes
	1.0	7/30/2018	Final Datasheet
	2.0	2/15/2018	typo corrected
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